

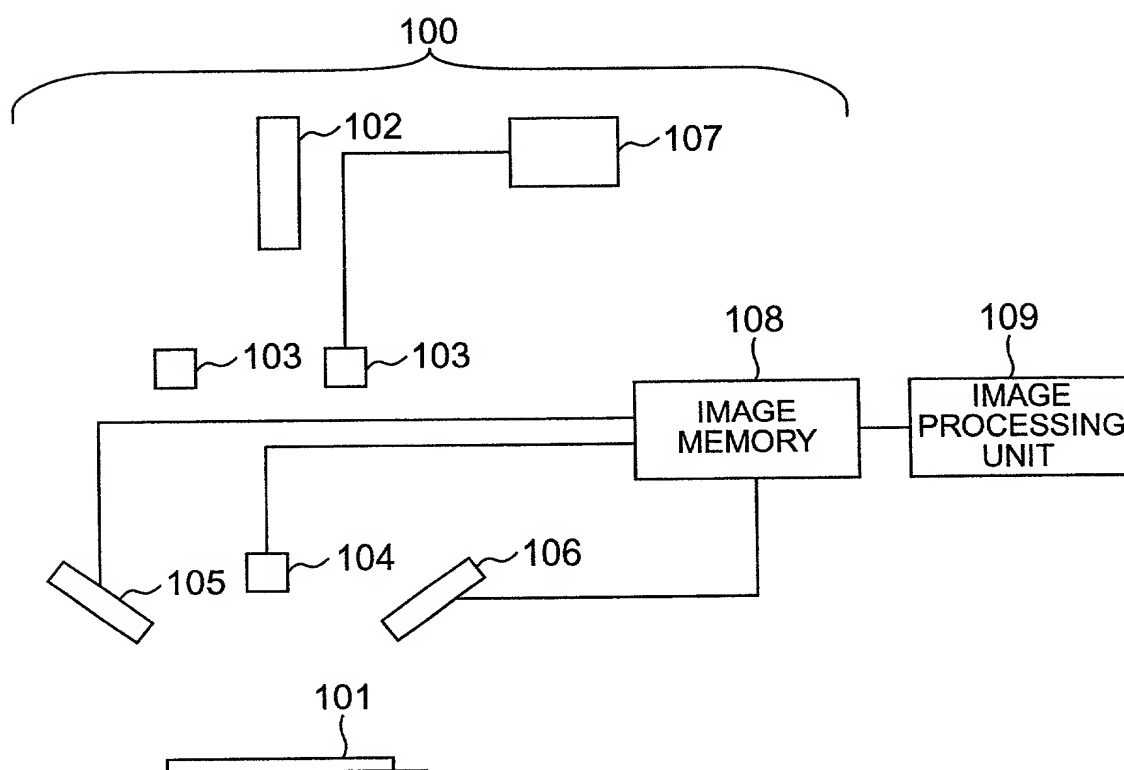
Applicant: Toshifumi Honda, *et al.*

Title: Defect Inspection Method

Atty Docket No. 16869S-043200

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FIG. 1



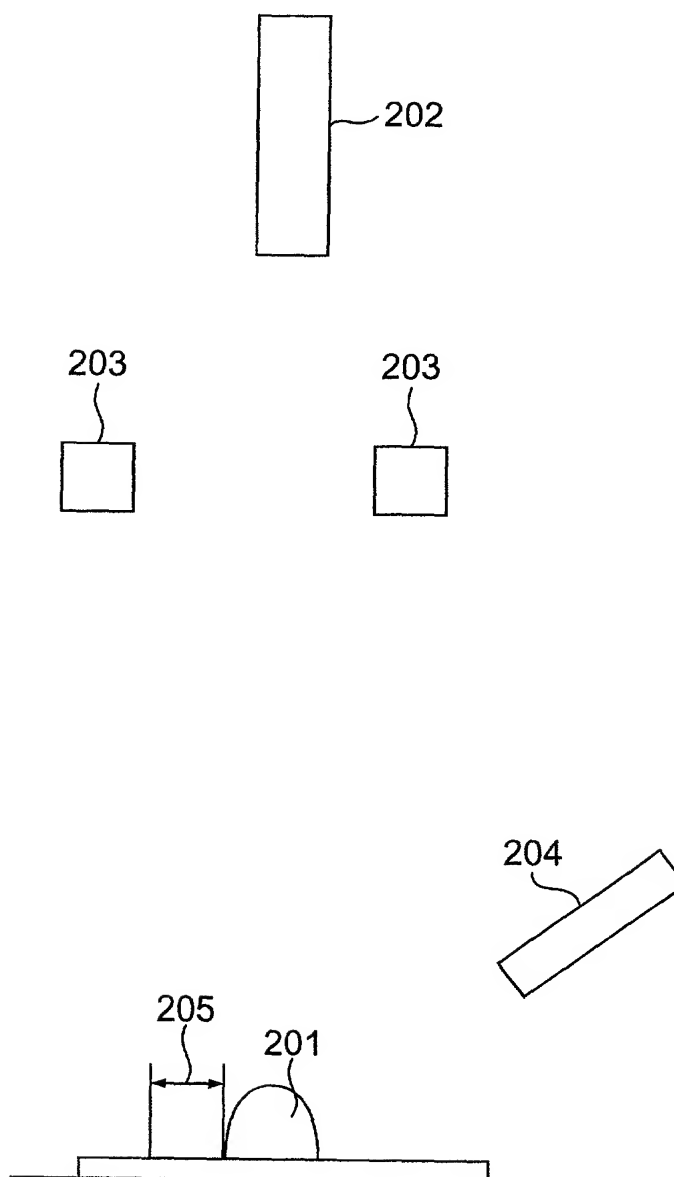
Applicant: Toshifumi Honda, et al.

Title: Defect Inspection Method

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FIG. 2



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FIG. 3

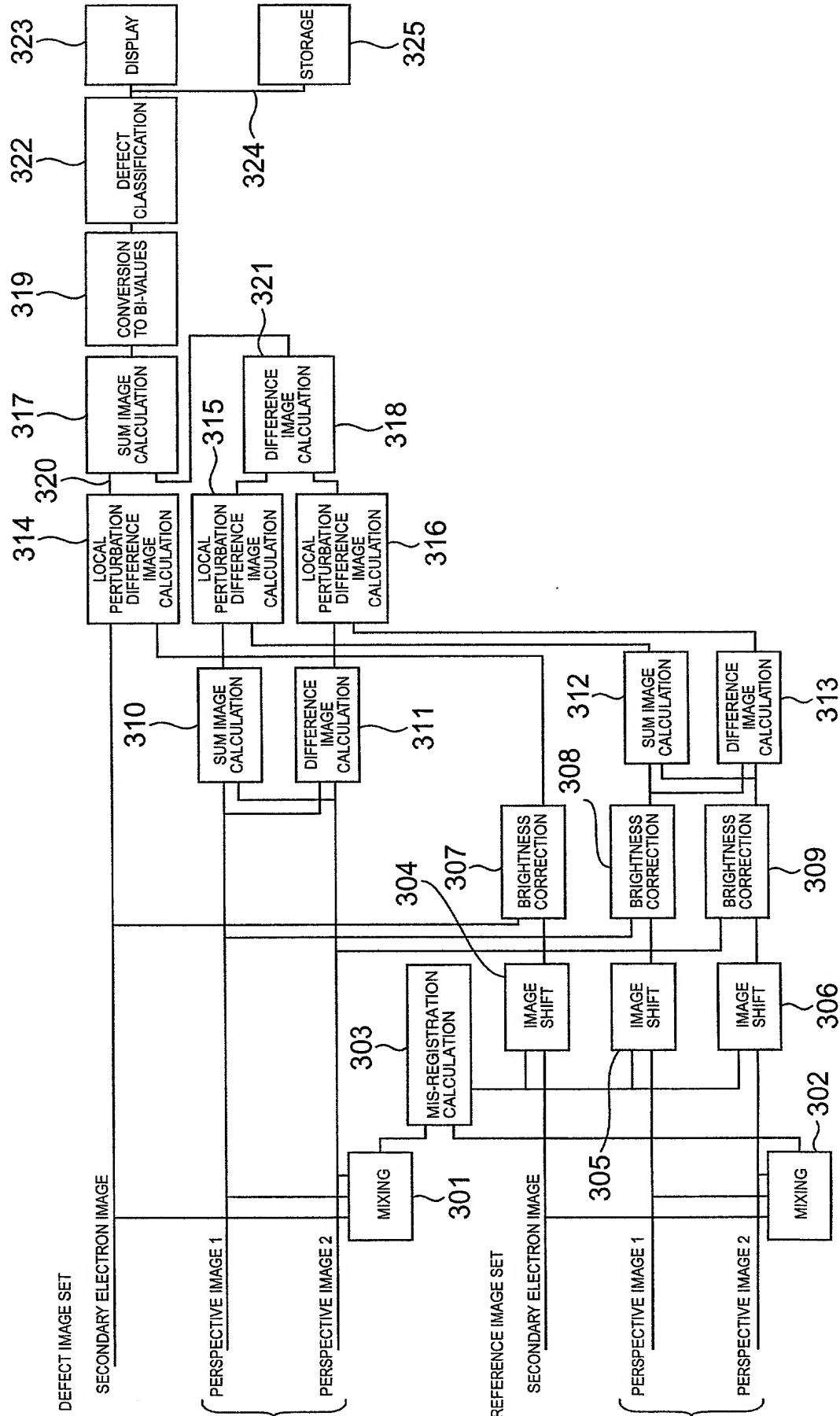


FIG. 4

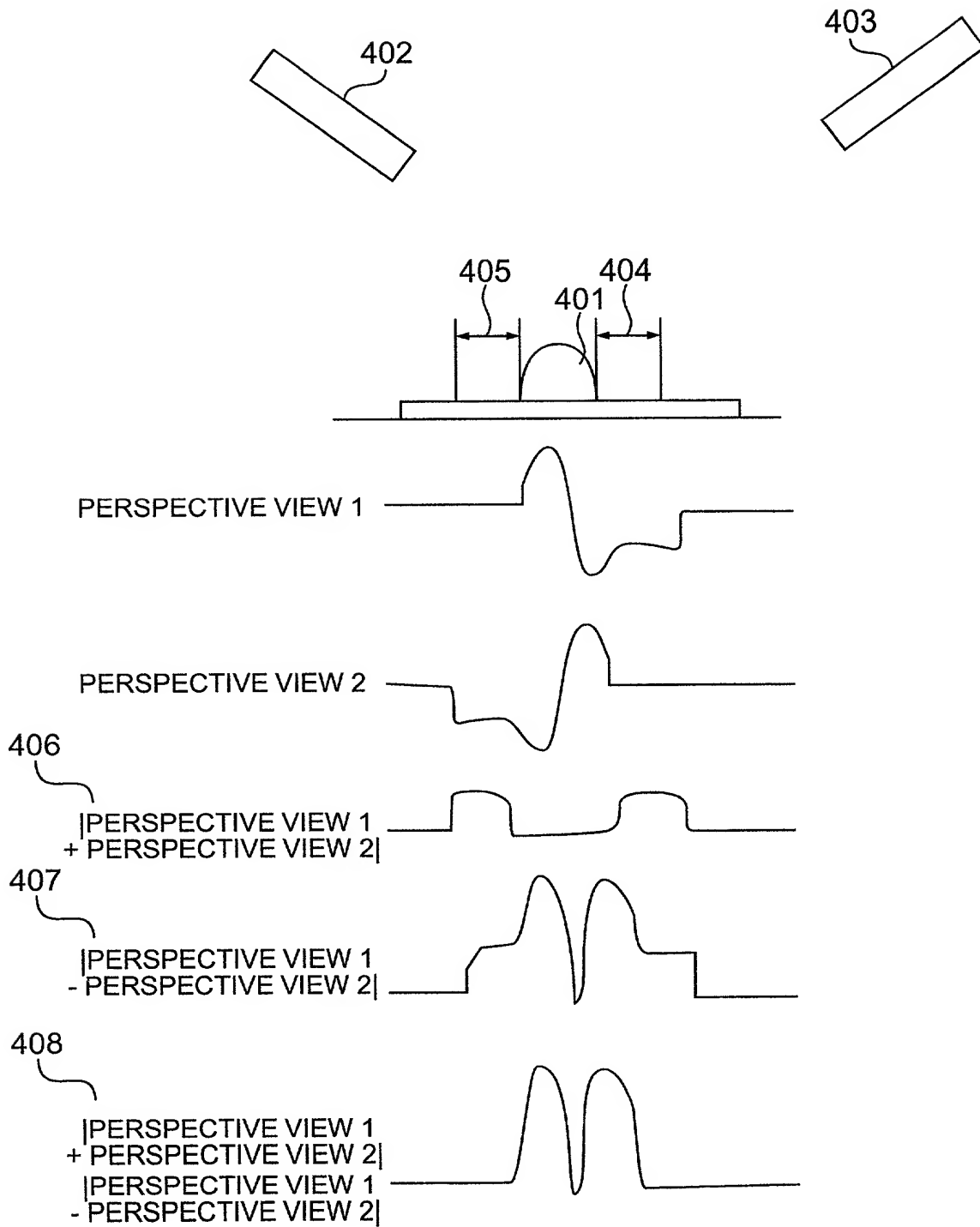
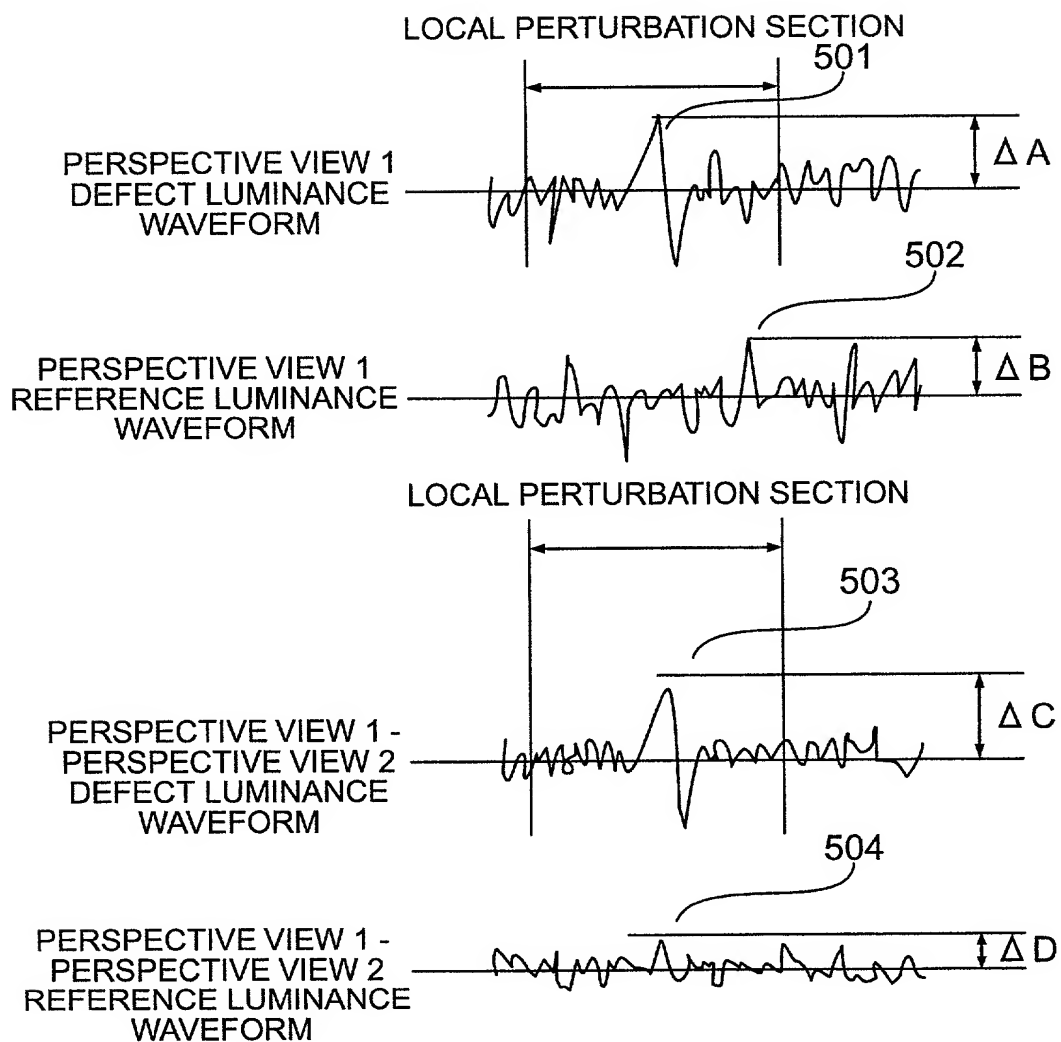


FIG. 5



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FIG. 6

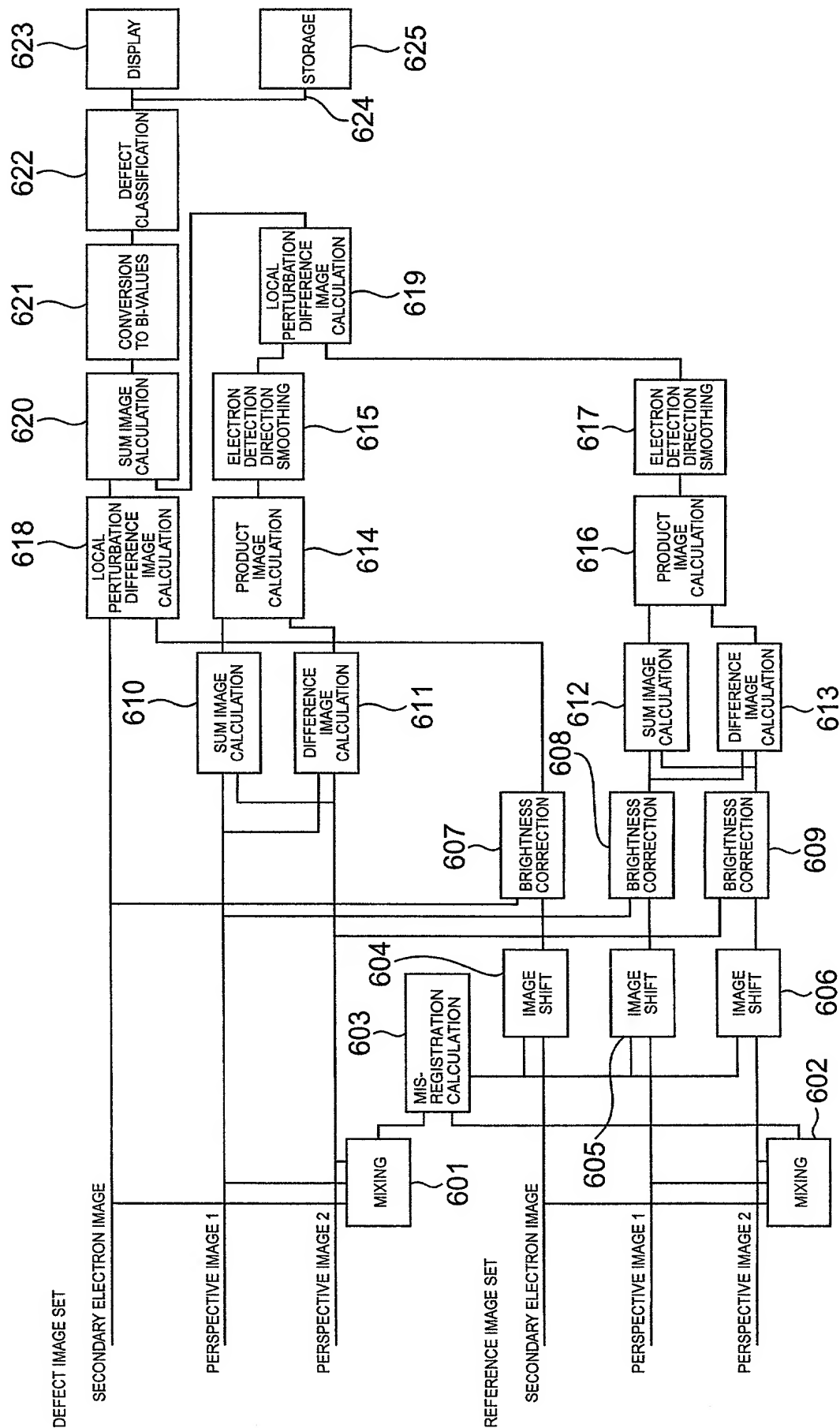


FIG. 7

DEFECT IMAGE WAVEFORM

LOCAL PERTURBATION SECTION

REFERENCE
IMAGE WAVEFORM

701

702

LOCAL PERTURBATION
DIFFERENCE WAVEFORM

16869S-043200-23